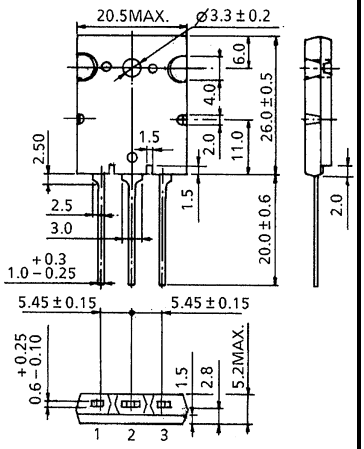
TOSHIBA TRANSISTOR SILICON NPN TRIPLE DIFFUSED MESA TYPE

2SC5589

HORIZONTAL DEFLECTION OUTPUT FOR
HIGH RESOLUTION DISPLAY, COLOR TV
HIGH SPEED SWITCHING APPLICATIONS

- High Voltage : V_{CBO} = 1500 V
- Low Saturation Voltage : $V_{CE\ (sat)}$ = 3 V (Max.)
- High Speed : t_f (2) = 0.1 μs (Typ.)

Unit: mm



JEDEC	—
JEITA	—
TOSHIBA	2-21F2A

Weight: 9.75 g (typ.)

ABSOLUTE MAXIMUM RATINGS (Tc = 25°C)

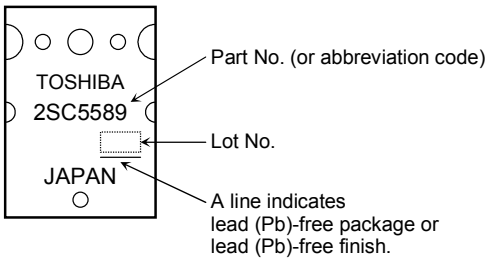
CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector−Base Voltage		V_{CBO}	1500	V
Collector−Emitter Voltage		V_{CEO}	750	V
Emitter−Base Voltage		V_{EBO}	5	V
Collector Current	DC	I_C	18	A
	Pulse	I_{CP}	36	
Base Current		I_B	9	A
Collector Power Dissipationc		P_C	200	W
Junction Temperature		T_j	150	°C
Storage Temperature Range		T_{stg}	−55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

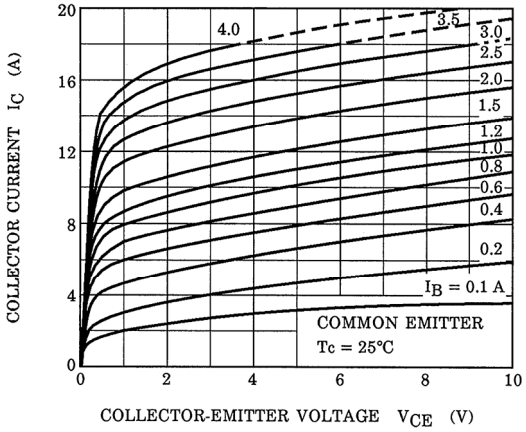
ELECTRICAL CHARACTERISTICS (T_C = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Collector Cut−off Current		I_{CBO}	V_{CB} = 1500 V, I_E = 0	—	—	1	mA
Emitter Cut−off Current		I_{EBO}	V_{EB} = 5 V, I_C = 0	—	—	100	μA
Collector−Emitter Breakdown Voltage		$V_{(BR)\ CEO}$	I_C = 10 mA, I_B = 0	750	—	—	V
DC Current Gain		$h_{FE\ (1)}$	V_{CE} = 5 V, I_C = 2 A	22	—	48	—
		$h_{FE\ (2)}$	V_{CE} = 5 V, I_C = 7 A	9	—	18	
		$h_{FE\ (3)}$	V_{CE} = 5 V, I_C = 14 A	5	—	8	
Collector−Emitter Saturation Voltage		$V_{CE\ (sat)}$	I_C = 14 A, I_B = 3.5 A	—	—	3	V
Base−Emitter Saturation Voltage		$V_{BE\ (sat)}$	I_C = 14 A, I_B = 3.5 A	—	1.0	1.5	V
Transition Frequency		f_T	V_{CE} = 10 V, I_C = 0.1 A	—	2	—	MHz
Collector Output Capacitance		C_{ob}	V_{CB} = 10 V, I_E = 0, f = 1 MHz	—	240	—	pF
Switching Time	Storage Time	$t_{stg\ (1)}$	I_{CP} = 9 A, I_{B1} (end) = 1.3 A f_H = 64 kHz	—	2.7	3	μs
	Fall Time	$t_{f\ (1)}$		—	0.2	0.3	
	Storage Time	$t_{stg\ (2)}$	I_{CP} = 7.5 A, I_{B1} (end) = 1.1 A f_H= 100 kHz	—	1.8	2	μs
	Fall Time	$t_{f\ (2)}$		—	0.1	0.15	

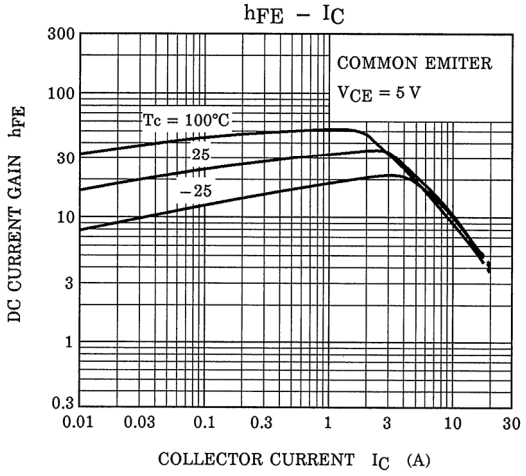
Marking



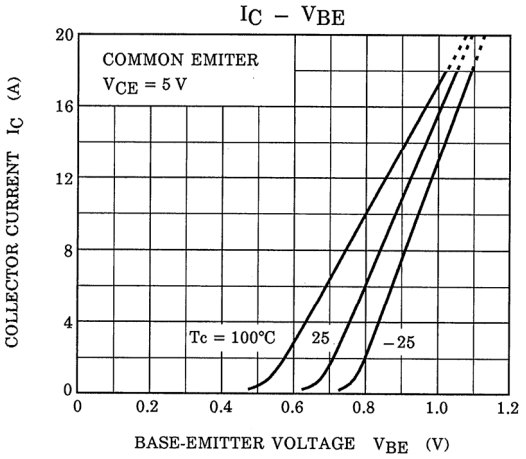
$I_C - V_{CE}$



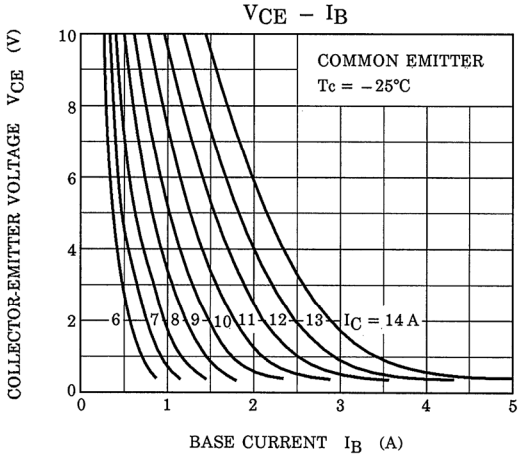
$h_{FE} - I_C$



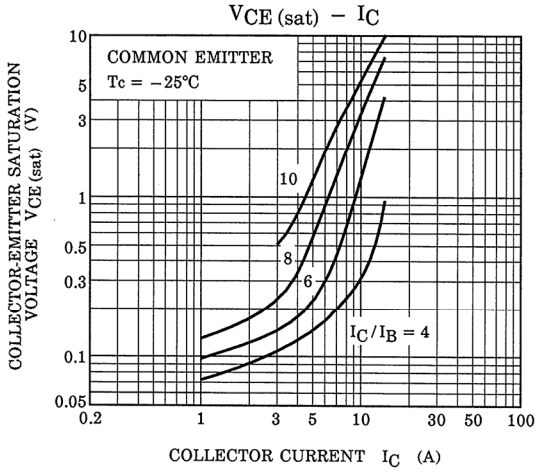
$I_C - V_{BE}$



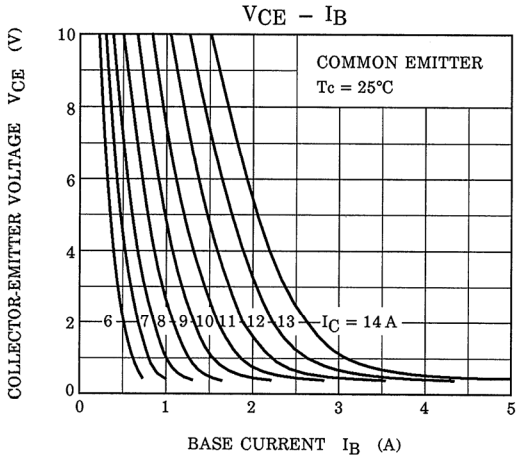
V_{CE} – I_B



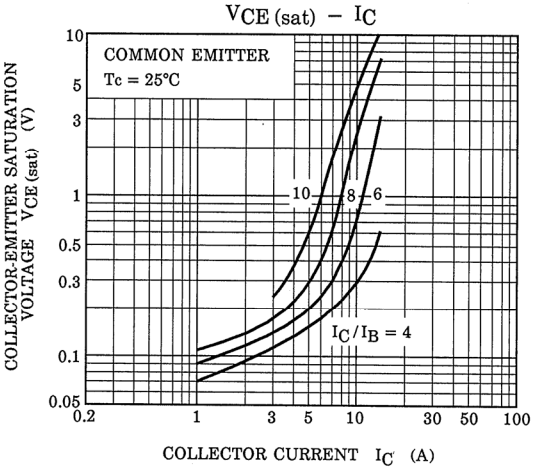
$V_{CE\,(sat)}$ – I_C



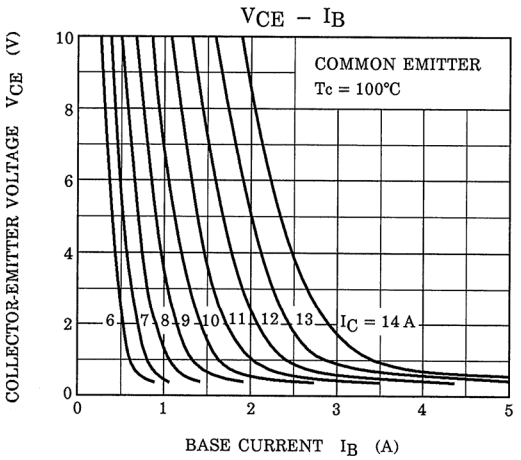
V_{CE} – I_B



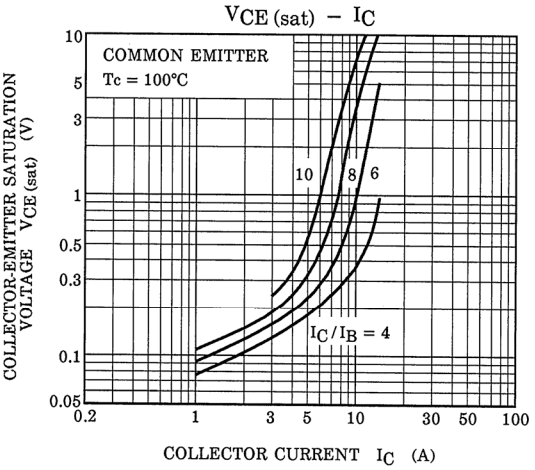
$V_{CE\,(sat)}$ – I_C



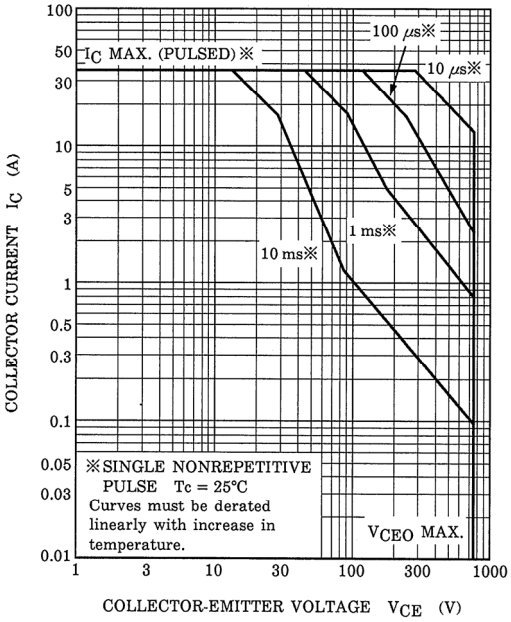
V_{CE} – I_B



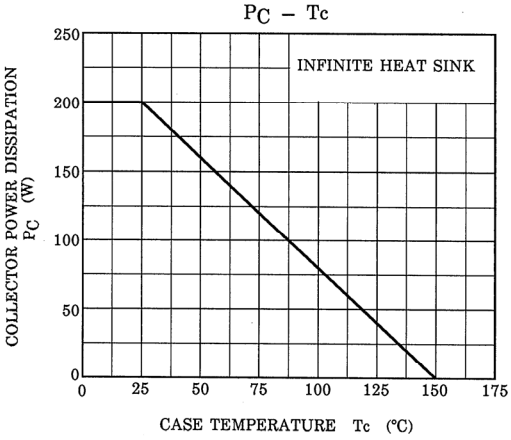
$V_{CE\,(sat)}$ – I_C



SAFE OPERATING AREA



P_C – Tc



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